

## **Quarterly Reliability Monitoring Results**

## Quarters: Q3/2021 to Q4/2022

Based on structural similarity

Supplier		User Part Number					
Nexperia B.V.		PMEG4020EP					
Name of Laboratory  Assembly reliability labs  Based on AEC-Q101 Test		Part Description					
		Nexperia DHAM Schottky					
		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113					
		Bake Tamb = 125 °C	24 hours				
	PC	Soak Tamb = 85 °C, RH = 85%	168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	1168	66640	0	
		MIL-STD-750-1					
	HTRB	M1038 Method A Tj = Tjmax, Vr = 100% of max. datasheet					
	High Temperature Reverse Bias	reverse voltage <sup>[1]</sup>		. ==		_	
# B1	DIdS	reverse voltage-	1000 hours	152	9440	0	
	тс	JESD22-A104					
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	240	1.4000	0	
# A4	remperature cycling	os e to filiax, not to exceed 150 e	1000 cycles	240	14800	0	
	UHAST	JESD22-A118					
# A3 or	Unbiased HAST	Tamb = 130 °C, RH = 85 %		240	14800	0	
		JESD22-A102	– 96 hours				
	AC	Tamb = 121 °C, RH = 100 %					
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)					
	НЗТRВ	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1], [2]</sup>	1000 hours	240	14800	0	
		MIL-STD-750 Method 1037					
	IOL	ton = toff, devices powered to insure $\Delta Tj$ =					
# A5	Intermittent Operating Life	100 °C for 15000 cycles	1000 hours	264	16720	0	
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	184	5520	0	
	SD	1.070.000					
# C10	Solderability	J-STD-002		501	5010	0	

<sup>[1]</sup> The physical limitations of Schottky diodes have to be considered (thermal runaway).

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Schottky	9440	0	0,45	2,22E+09

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<sup>[2]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.